




PCN Number:		20151215001		PCN Date:		12/16/2015	
Title:		LM43603PWPx Die Revision Change					
Customer Contact:		PCN Manager		Dept:		Quality Services	
Proposed 1st Ship Date:		3/16/2016		Estimated Sample Availability:		Date provided at sample request.	
Change Type:							
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials		
<input checked="" type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification		
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process		
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process		
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process		
<input type="checkbox"/>		<input type="checkbox"/>	Part number change				
PCN Details							
Description of Change:							
This notification is to inform of a die revision change to select devices. Design changes were made to improve the feedback voltage accuracy and ESD HBM rating. The design changes do not affect the device's guaranteed datasheet specifications or electrical performance. Affected devices are listed in the product affected section of this document.							
Reason for Change:							
Improved product performance							
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):							
None							
Changes to product identification resulting from this PCN:							
Die Rev designator will change as shown in the table and sample label below:							
Current		New					
Die Rev [2P]		Die Rev [2P]					
B		C					
Sample product shipping label (not actual product label)							
 MADE IN: Malaysia 2DC: 2d:						(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO: USA (22L) ASO: MLA (23L) ACO: MYS	
MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L)T0:1750							
Product Affected:							
LM43602PWP	LM43602PWPT	LM43603PWPR	LM43603PWPT				
LM43602PWPR	LM43603PWP						

Qualification Report

LM43603QPWPQ1

Approved 05/01/2015

Product Attributes

Attributes	Qual Device: LM43603QPWPQ1
Assembly Site	TAI / TITL
Package Family	PWP
Wafer Fab Site	DMOS5
Wafer Process Technology	Power BiCMOS

- Qual Device LM43603QPWPQ1 is qualified at LEVEL3-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: LM43603QPWPQ1
HAST	Biased HAST, 110C/85%RH	264 hours	3/231/0
AC	Autoclave 121C	96 hours	3/231/0
TC	Temperature Cycle, -65/150C	500 cycles	2/231/0
PTC	Power Temperature Cycle, -40/125C	1000 cycles	1/45/0
HTSL	High Temperature Storage Life, 150C	1000 cycles	Substituted by Data Retention in EDR
EDR	NVM Endurance, Data Retention, and Operational Life	-	3/77/0
HTOL	Life Test, 150C	408 hours	3/231/0
ELFR	Early Life Failure Rate, 150C	24 hours	3/2400/0
HBM	ESD - HBM	2500V	1/3/0
CDM	ESD - CDM	1000V	1/3/0
LU	Latch-up	(Per JESD78)	1/6/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass

Preconditioning was performed for THB, Biased HAST, AC, uHAST & TC samples, as applicable.

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com